Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination
10/696,294	YONEYAMA, AKIRA

Y. Lee

Art Unit Examiner 2621

SEARCHED				
Class	Subclass	Date	Examiner	
375	240.01 240.12 240.13 240.16	5/23/2006	YL	
	240.23			
	240.25			
	240.26			
H04N	7/12			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
375	240.16	5/23/2006	YL	
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SEARCH NOT (INCLUDING SEARCH	TES STRATEGY	)
	DATE	EXMR
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